

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10585733	ICHIKAWA, TAKESHI
	Examiner	Art Unit
	SELIM AHMED	2826

SEARCHED

Class	Subclass	Date	Examiner
438	57, 59, 60, 73, 78	11/9/08	/sa/
257	291, 292	11/9/08	/sa/
	Updated search	6/7/2009	/sa/

SEARCH NOTES

Search Notes	Date	Examiner
Test search such as, buried channel, surface channel, image sensor, CMOS sensor, photoelectric, pixel, transistor, substrate and their boolean combinations were searched.	11/9/08	/sa/
Updated search	6/7/2009	/sa/

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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